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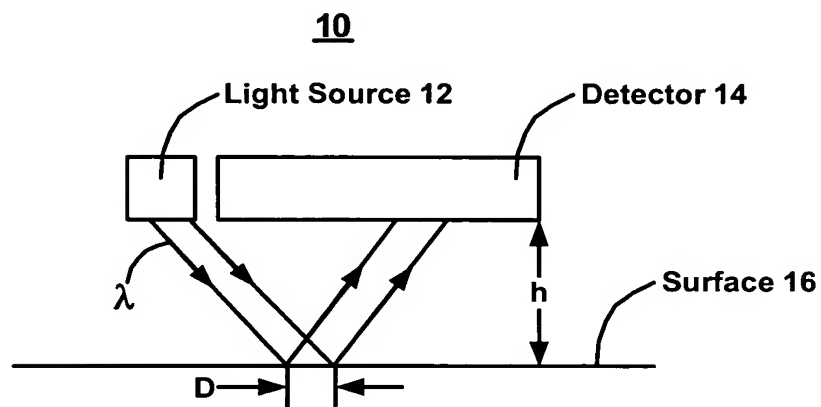


FIG. 1

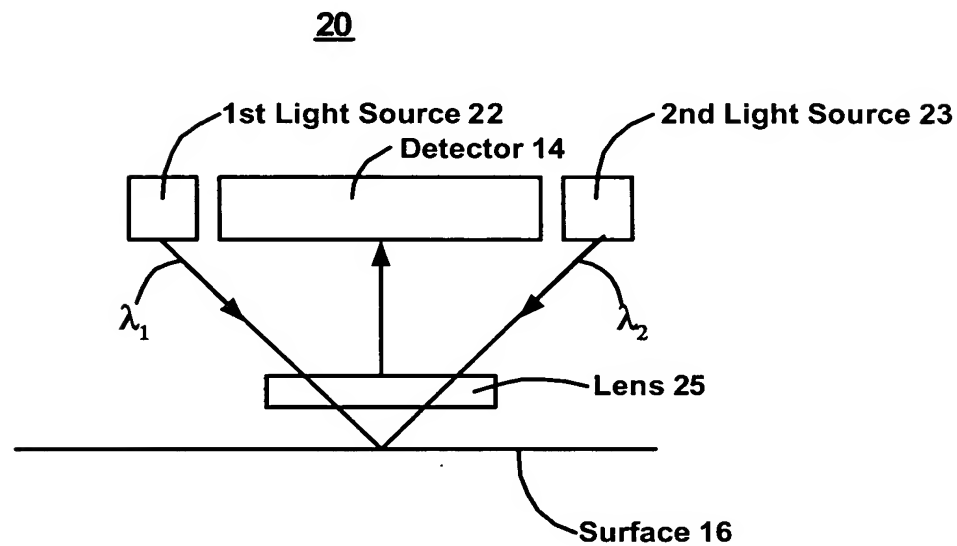


FIG. 2

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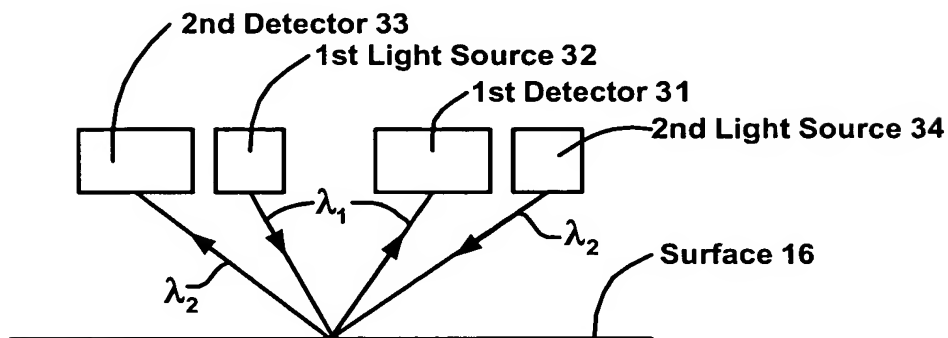


FIG. 3

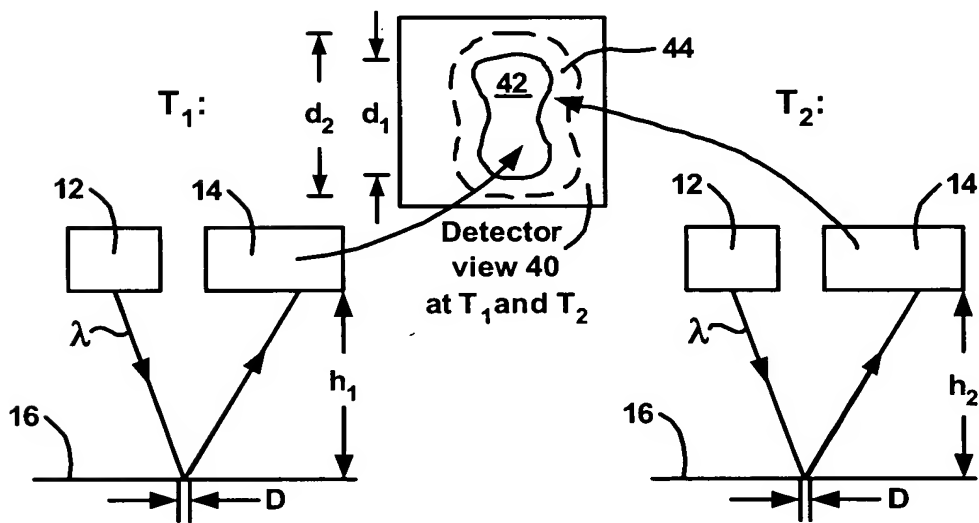


FIG. 4

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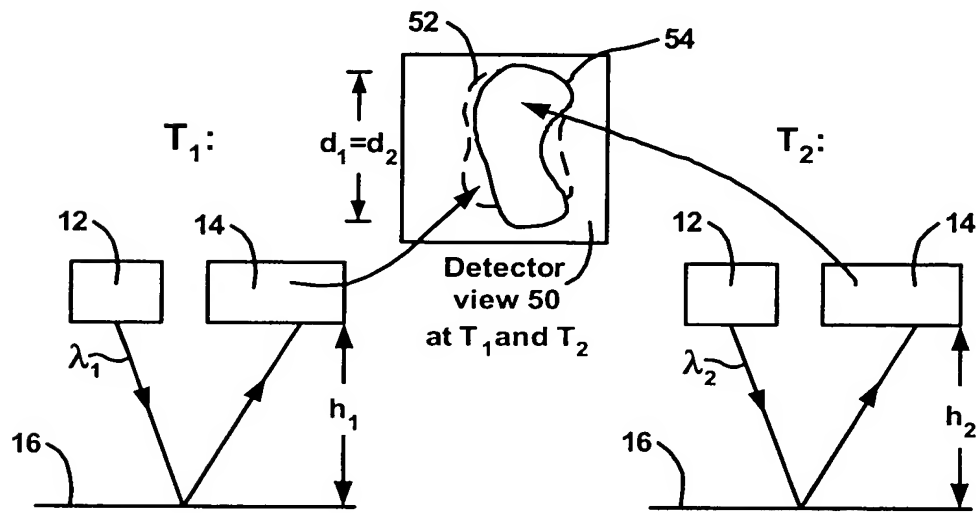


FIG. 5

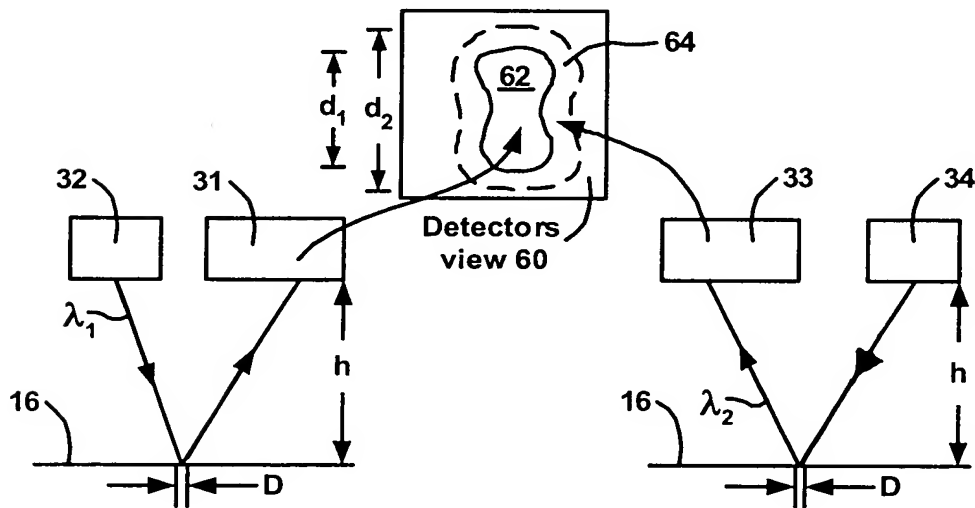


FIG. 6

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70

DETECT A 1st SPECKLE PATTERN PRODUCED BY LIGHT AT A 1st WAVELENGTH
THAT IS REFLECTED FROM A SURFACE AT A 1st DISTANCE TO THE SURFACE

72

DETECT A 2nd SPECKLE PATTERN PRODUCED BY LIGHT AT A 2nd
WAVELENGTH THAT IS REFLECTED FROM THE SURFACE AT A 2nd DISTANCE TO
THE SURFACE, WHEREIN THE 1st AND 2nd WAVELENGTHS ARE SELECTED SO
THAT A MEASURE OF THE 1st SPECKLE PATTERN AND A MEASURE OF THE 2nd
SPECKLE PATTERN ARE APPROXIMATELY EQUAL

74

MEASURE DISTANCE TO THE SURFACE USING THE RATIO OF THE 1st AND 2nd
WAVELENGTHS

76

FIG. 7

80

DETECT A 1st SPECKLE PATTERN PRODUCED BY REFLECTED LIGHT AT A
1st WAVELENGTH

82

DETECT A 2nd SPECKLE PATTERN PRODUCED BY REFLECTED LIGHT AT A
2nd WAVELENGTH

84

MEASURE DISTANCE BETWEEN AN OPTICAL DEVICE AND A SURFACE
USING QUANTIFIABLE VALUES ASSOCIATED WITH THE 1st AND 2nd
SPECKLE PATTERNS

86

FIG. 8